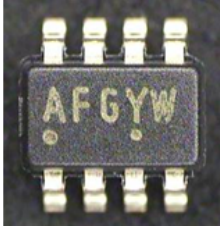




Title of Change:	Device Marking change and additional Test site for CAT5171TBI-50GT3		
Proposed first ship date:	4 September 2017		
Contact information:	Contact your local ON Semiconductor Sales Office or <Shero.Gao@onsemi.com>		
Samples:	Contact your local ON Semiconductor Sales Office		
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Francis.Lualhati@onsemi.com>.		
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.		
Change Part Identification:	Affected product from ON semiconductor with date code "HJ" representing WW36, 2017 and greater may be tested in UTAC Thai Limited or ON Leshan China and with the new marking style.		
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☒ Test Change ☒ Other <u>Marking & Test Site</u>		
Change Sub-Category(s):	☒ Manufacturing Site Change/Addition ☐ Material Change ☐ Datasheet/Product Doc change ☐ Manufacturing Process Change ☐ Product specific change ☒ Shipping/Packaging/Marking ☐ Other: _____		
Sites Affected:	☐ All site(s) ☐ not applicable ☒ ON Semiconductor site(s) : ON Leshan, China ☒ External Foundry/Subcon site(s) UTAC Thai Limited		
Description and Purpose:			
This Product Change Notice is to notify customers of the change in product marking and of an additional test site (ON Semiconductor Leshan, LPS) for CAT5171TBI-50GT3. As of September 4th, 2017 (WW36), ON will convert production to the new marking on parts tested at UTAC and LPS. Current marking will continue through September 4th, 2017 (WW36) and may be tested at either LPS or UTAC. Parts with the current date code are considered valid parts and will not be exchanged or recalled. The marking change is to match the ON standard marking as shown in the diagram below. Under the current ON standard marking, there will no longer be bottom marking. Parts will continue to be tested to the same datasheet specifications at both locations, but may be tested on different test platforms.			
Marking	Before Change Description	After Change Description	
Marking diagram			
Marking indication	AF = 50 kΩ Y = Production Year (Last Digit) M = Production Month (1 – 9, A, B, C)	AF = 50 kΩ A = Assembly Location YW = Production Year and Week	



Before		After (No Bottom Marking)	
UTAC Bottom Marking	After Top Marking	UTAC Top Marking	LPS Top Marking
			

Reliability Data Summary:

Not Applicable due to Change Category. Test Site Change is expected to have no impact to Reliability data.

Electrical Characteristic Summary:

Not Applicable due to Change Category. Test Site Change is expected to have no impact to Electrical Characteristics of the Products.

List of affected Standard Parts:

Part Number	Qualification Vehicle
CAT5171TBI-50GT3	CAT5171TBI-50GT3